Search Notes			

Application/Control No.	Applicant(s)/Patent und Reexamination	er
09/821,565	ISHIKAWA, MARK M.	
Examiner	Art Unit	
Tongoc Tran	2134	

SEARCHED				
Class	Subclass	Date	Examiner	
713	163	6/21/2006	п	
726	11,12,13	6/21/2006	ТТ	
726	3,22	6/21/2006	π	
709	238,242	6/21/2006	π	
370	389,390,	6/21/2006	π	
370	392,401,	6/21/2006	π	
370	432	6/21/2006	π	
		·		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
713	163	6/21/2006	ΤΤ	
726	3, 11-13,	6/21/2006	π	
726	3,22	6/21/2006	π	
370/389,39	38,242 90,392,401, 32	6/21/2006	тт	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East	6/21/2006	π
EIC search	6/21/2006	π
Consult: Derrick Ferris AU: 2616; Kenneth Coulter AU: 2141; Zand Kambiz AU: 2132	6/21/2006	П
Inventor Search	6/21/2006	π
·		